<u>What Is Claimed Is</u>:

1.   A method for activating a microprocessor arranged as a part of a microcontroller, within a framework of a boundary scan test procedure according to IEEE standard 1149, in accordance with a JTAG interface, comprising the step of:

activating the JTAG interface of the microprocessor in accordance with a test routine that is executable on the microprocessor.

2.   The method according to claim 1, wherein I/O ports of the microprocessor are connected to pins of the JTAG interface, the method further comprising the step of:

activating the pins of the JTAG interface in accordance with the test routine via the I/O ports.

3.   The method according to claim 2, further comprising the step of:

performing at least one of a setting operation and a reading operation with respect to the pins of the JTAG interface in accordance with a stipulated test sequence in the test routine.

4.   The method according to claim 1, further comprising the step of:

causing the test routine to provide a test data stream to the JTAG interface within the framework of the boundary scan test procedure.

5.   The method according to claim 2, further comprising the steps of:

switching the I/O ports of the microprocessor in accordance with the test routine for a predefined duration to output ports and to high; and

measuring levels present at an interface of the microcontroller.

6.   The method according to claim 3, further comprising the steps of:

switching the I/O ports of the microprocessor in accordance with the test routine for a predefined duration to input ports; and

applying defined values to an interface of the microcontroller in accordance with the stipulated test sequence.

7. The method according to claim 6, further comprising the steps of:

reading values present at the pins of the JTAG interface via the I/O ports of the microprocessor; and

storing the values present at the pins of the JTAG interface in a memory area of the microcontroller.

8. The method according to claim 7, further comprising the step of:

reading out the values present at the pins of the JTAG interface and stored in the memory area via the interface of the microcontroller.

9. The method according to claim 1, wherein:

the microcontroller is arranged in a control unit of a motor vehicle.

10. A microcontroller, comprising:

at least one microprocessor capable of being activated, within a framework of a boundary scan test procedure according to IEEE standard 1149, by a JTAG interface of the at least one microprocessor, wherein:

the at least one microprocessor includes an arrangement for activating the JTAG interface by a test routine capable of being executed on the at least one microprocessor.

11. The microcontroller according to claim 10, wherein:

the arrangement includes PAD cells of the microprocessor and connecting leads from the PAD cells to pins of the JTAG interface, the PAD cells including an input/output port function.

12. The microcontroller according to claim 10, wherein:

the microcontroller includes an interface, wherein one of levels present can be measured and defined values can be applied from outside the microcontroller.